







CSD25484F4 SLPS551B - MAY 2015 - REVISED FEBRUARY 2022

CSD25484F4 -20-V P-Channel FemtoFET™ MOSFET

1 Features

- Low on-resistance
- Ultra-low Q_a and Q_{ad}
- Low-threshold voltage
- Ultra-small footprint (0402 case size)
 - 1.0 mm × 0.6 mm
- · Ultra-low profile
 - 0.2-mm height
- Integrated ESD protection diode
 - Rated > 4-kV HBM
 - Rated > 2-kV CDM
- Lead and halogen free
- RoHS compliant

2 Applications

- Optimized for load switch applications
- Optimized for general purpose switching applications
- **Battery applications**
- Handheld and mobile applications

3 Description

This 80-mΩ, –20-V, P-Channel FemtoFET™ MOSFET is designed and optimized to minimize the footprint in many handheld and mobile applications. This technology is capable of replacing standard small signal MOSFETs while providing at least a 60% reduction in footprint size.

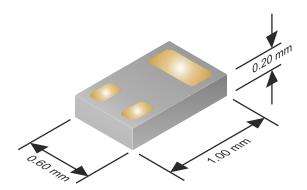


Figure 3-1. Typical Package Dimensions

Product Summary

T _A = 25°	С	TYPICAL VA	UNIT		
V _{DS}	Drain-to-source voltage -20				
Qg	Gate charge total (-4.5 V)	1090	рC		
Q _{gd}	Gate charge gate-to-drain		рC		
R _{DS(on)}		V _{GS} = -1.8 V	405		
	Drain-to-source	V _{GS} = -2.5 V	150		
	on-resistance	V _{GS} = -4.5 V	93	mΩ	
		V _{GS} = -8.0 V	80		
V _{GS(th)}	Threshold voltage	-0.95	V		

Device Information

DEVICE	QTY	MEDIA	PACKAGE ⁽¹⁾	SHIP
CSD25484F4	3000		Femto (0402)	Tape
CSD25484F4T	250	7-Inch Reel	1.00-mm × 0.60-mm Land Grid Array (LGA)	and Reel

For all available packages, see the orderable addendum at the end of the data sheet.

Absolute Maximum Ratings

Absolute maximum ratings								
°C	VALUE	UNIT						
Drain-to-source voltage	-20	٧						
Gate-to-source voltage	-12	٧						
Continuous drain current ⁽¹⁾	-2.5	Α						
Pulsed drain current ⁽¹⁾ (2)	-22	Α						
Continuous gate clamp current	-35	mA						
Pulsed gate clamp current ⁽²⁾	-350	шА						
Power dissipation ⁽¹⁾	500	mW						
Human-body model (HBM)	4	kV						
Charged-device model (CDM)	2	KV						
Operating junction, storage temperature	-55 to 150	°C						
	Porain-to-source voltage Gate-to-source voltage Continuous drain current(1) Pulsed drain current(1) (2) Continuous gate clamp current Pulsed gate clamp current(2) Power dissipation(1) Human-body model (HBM) Charged-device model (CDM) Operating junction,	Drain-to-source voltage -20 Gate-to-source voltage -12 Continuous drain current(1) -2.5 Pulsed drain current(1) (2) -22 Continuous gate clamp current -35 Pulsed gate clamp current(2) -350 Power dissipation(1) 500 Human-body model (HBM) 4 Charged-device model (CDM) 2 Operating junction, -55 to 150						

- Typical $R_{\theta JA} = 85^{\circ}C/W \text{ on } 1-\text{in}^2 (6.45-\text{cm}^2), 2-\text{oz}$ (0.071-mm) thick Cu pad on a 0.06-in (1.52-mm) thick FR4 PCB.
- Pulse duration ≤ 100 µs, duty cycle ≤ 1%. (2)

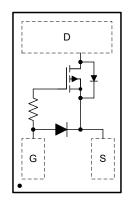


Figure 3-2. Top View



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5 Specifications

5.1 Electrical Characteristics

T_A = 25°C (unless otherwise stated)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
STATIC	CHARACTERISTICS					
BV _{DSS}	Drain-to-source voltage	V _{GS} = 0 V, I _{DS} = -250 μA	-20			V
I _{DSS}	Drain-to-source leakage current	V _{GS} = 0 V, V _{DS} = -16 V			-100	nA
I _{GSS}	Gate-to-source leakage current	V _{DS} = 0 V, V _{GS} = -12 V			-50	nA
V _{GS(th)}	Gate-to-source threshold voltage	$V_{DS} = V_{GS}, I_{DS} = -250 \mu A$	-0.7	-0.95	-1.2	V
		V _{GS} = -1.8 V, I _{DS} = -0.1 A		405	825	
В	Drain to course on registence	$V_{GS} = -2.5 \text{ V}, I_{DS} = -0.5 \text{ A}$		150	180	~ 0
R _{DS(on)}	Drain-to-source on-resistance	$V_{GS} = -4.5 \text{ V}, I_{DS} = -0.5 \text{ A}$		93	109	mΩ
		$V_{GS} = -8 \text{ V}, I_{DS} = -0.5 \text{ A}$		80	94	
9 _{fs}	Transconductance	V _{DS} = -10 V, I _{DS} = -0.5 A		3.5		S
DYNAMI	C CHARACTERISTICS					
C _{iss}	Input capacitance			175	230	pF
C _{oss}	Output capacitance	$V_{GS} = 0 \text{ V, } V_{DS} = -10 \text{ V,}$ f = 1 MHz		78	102	pF
C _{rss}	Reverse transfer capacitance	J = 1 Will2		5.5	7.2	pF
R_G	Series gate resistance			20		Ω
Qg	Gate charge total (–4.5 V)			1090	1415	рС
Q _{gd}	Gate charge gate-to-drain	V - 40VI - 05A		150		рС
Q _{gs}	Gate charge gate-to-source	$V_{DS} = -10 \text{ V}, I_{DS} = -0.5 \text{ A}$		350		рС
Q _{g(th)}	Gate charge at V _{th}			210		рС
Q _{oss}	Output charge	V _{DS} = -10 V, V _{GS} = 0 V		1290		рС
t _{d(on)}	Turnon delay time			9.5		ns
t _r	Rise time	$V_{DS} = -10 \text{ V}, V_{GS} = -4.5 \text{ V},$		5		ns
t _{d(off)}	Turnoff delay time	$I_{DS} = -0.5 \text{ A}, R_G = 10 \Omega$		18		ns
t _f	Fall Time			8.5		ns
DIODE C	CHARACTERISTICS					
V _{SD}	Diode forward voltage	$I_{SD} = -0.5 \text{ A}, V_{GS} = 0 \text{ V}$		-0.75		V
Q _{rr}	Reverse recovery charge	V = 40 V I = 0.5 A didt = 400 A free		970		рС
t _{rr}	Reverse recovery time	V_{DS} = -10 V, I_F = -0.5 A, di/dt = 100 A/ μ s		7.5		ns

5.2 Thermal Information

 $T_A = 25$ °C (unless otherwise stated)

	THERMAL METRIC	TYPICAL VALUES	UNIT
D	Junction-to-ambient thermal resistance ⁽¹⁾	85	°C/W
$R_{\theta JA}$	Junction-to-ambient thermal resistance ⁽²⁾	245	C/VV

 ⁽¹⁾ Device mounted on FR4 material with 1-in² (6.45-cm²), 2-oz (0.071-mm) thick Cu.
 (2) Device mounted on FR4 material with minimum Cu mounting area.



5.3 Typical MOSFET Characteristics

 $T_A = 25$ °C (unless otherwise stated)

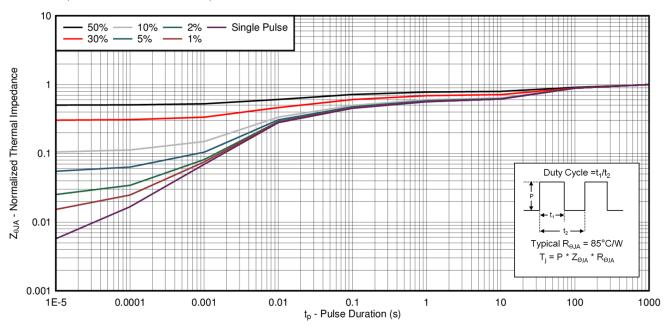
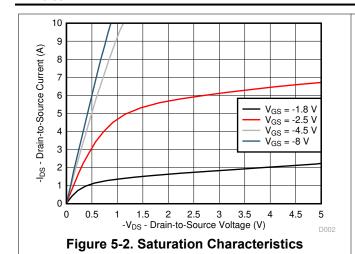
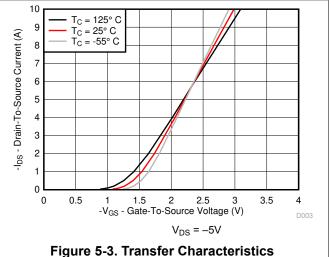
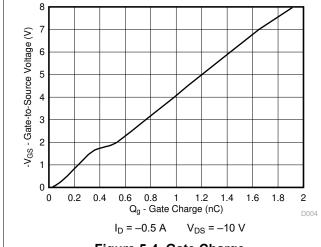


Figure 5-1. Transient Thermal Impedance







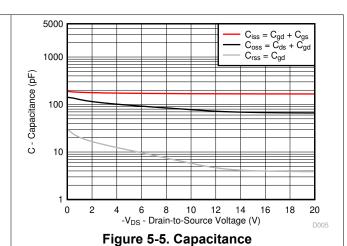


Figure 5-4. Gate Charge

1.25

1.15

1.05

0.95

0.85

0.75

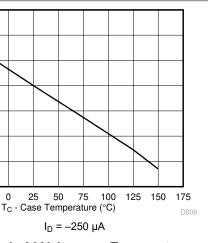
0.65

0.55

-75

-50 -25 0 25

-V_{GS(th)} - Threshold Voltage (V)



250 $T_{C} = 25^{\circ} \text{ C}, \ I_{D} = -0.5 \text{ A}$ $T_{C} = 125^{\circ} \text{ C}, \ I_{D} = -0.5 \text{ A}$ 225 (mD) 200 On-State Resistance 175 150 125 100 75 50 25 0 0 8 12 -V_{GS} - Gate-To-Source Voltage (V)

Figure 5-6. Threshold Voltage vs Temperature

50 75

Figure 5-7. On-State Resistance vs Gate-to-Source Voltage



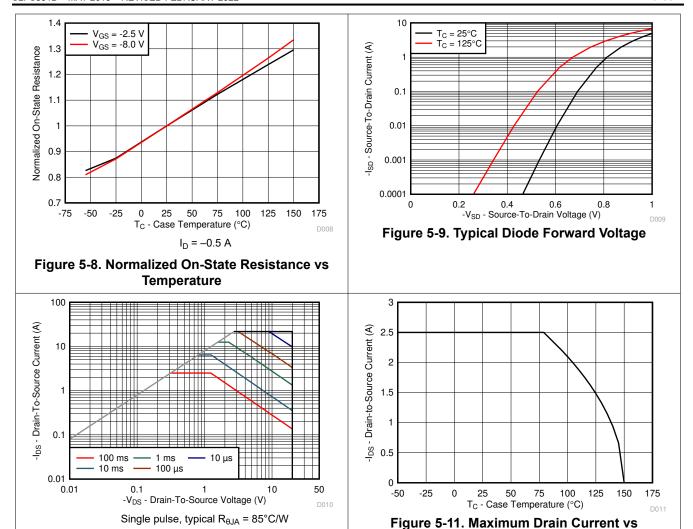


Figure 5-10. Maximum Safe Operating Area

Temperature

6 Device and Documentation Support

6.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

6.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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6.3 Trademarks

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6.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

6.5 Glossary

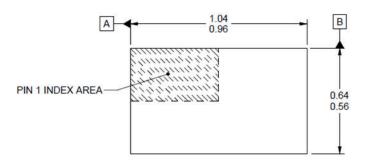
TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

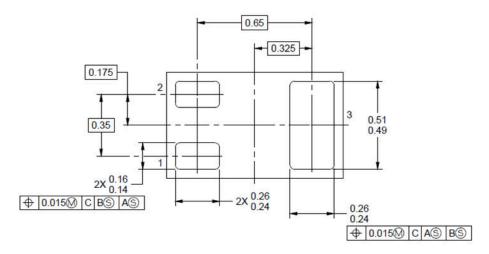
7 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

7.1 Mechanical Dimensions







- A. All linear dimensions are in millimeters (dimensions and tolerancing per AME T14.5M-1994).
- B. This drawing is subject to change without notice.
- C. This package is a PB-free solder land design.

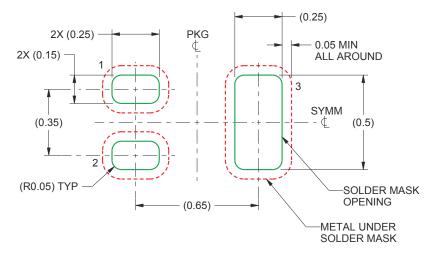
Table 7-1. Pin Configuration

Gonnigaration									
POSITION	DESIGNATION								
Pin 1	Gate								
Pin 2	Source								
Pin 3	Drain								

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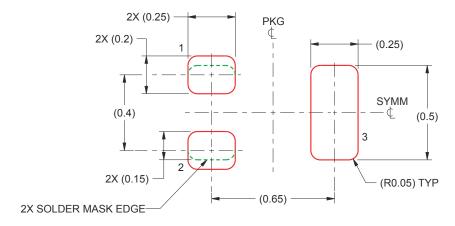


7.2 Recommended Minimum PCB Layout



- A. All dimensions are in millimeters.
- B. For more information, see FemtoFET Surface Mount Guide (SLRA003D).

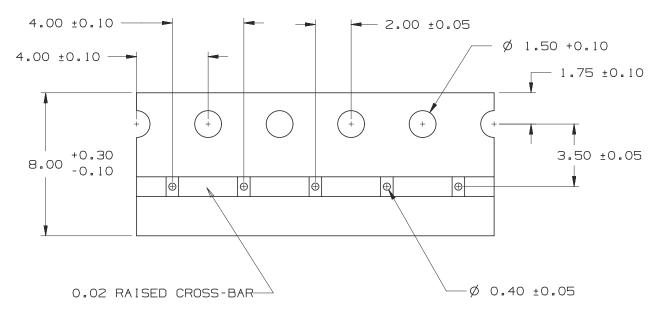
7.3 Recommended Stencil Pattern

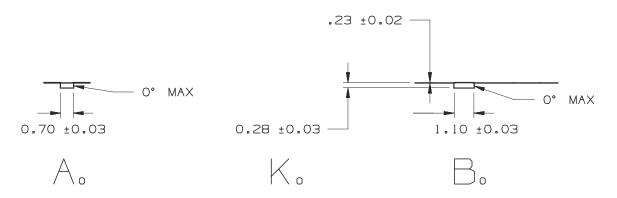


A. All dimensions are in millimeters.



7.4 CSD68830F4 Embossed Carrier Tape Dimensions





A. Pin 1 is oriented in the top-right quadrant of the tape enclosure (quadrant 2), closest to the carrier tape sprocket holes.

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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CSD25484F4	ACTIVE	PICOSTAR	YJJ	3	3000	RoHS & Green	NIAU	Level-1-260C-UNLIM	-55 to 150	G3	Samples
CSD25484F4T	ACTIVE	PICOSTAR	YJJ	3	250	RoHS & Green	NIAU	Level-1-260C-UNLIM	-55 to 150	G3	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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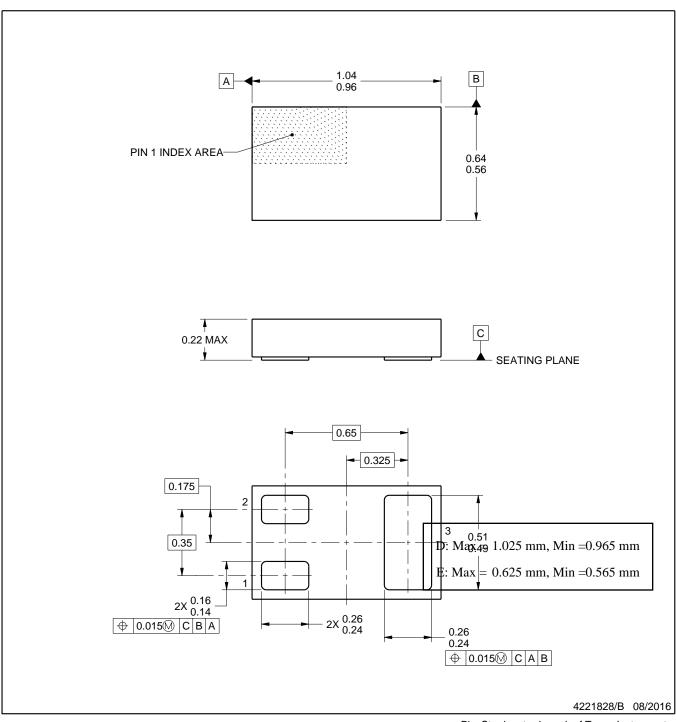


PACKAGE OPTION ADDENDUM

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NOTES:

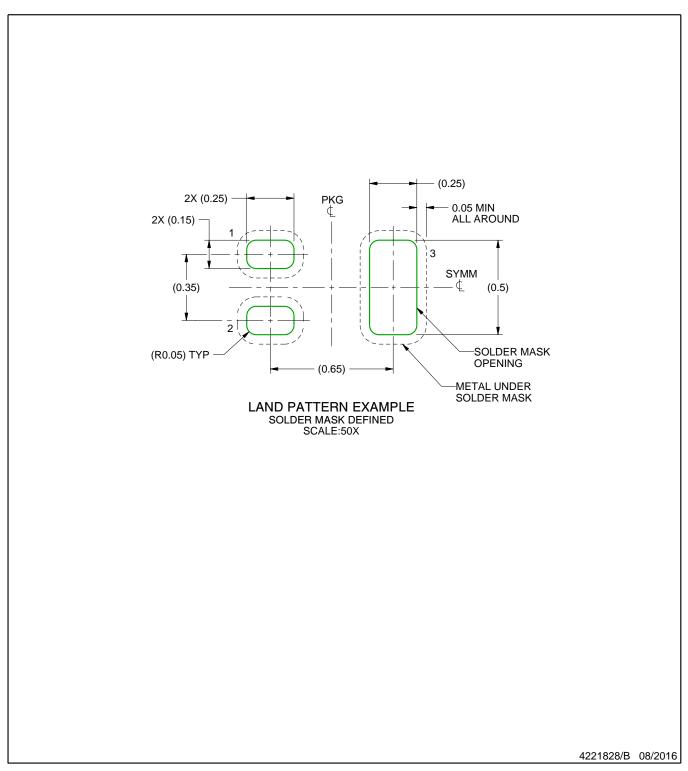
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- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M

 2. This drawing is subject to change without notice.
- 3. This package is a Pb-free bump design. Bump finish may vary. To determine the exact finish, refer to the device datasheet or contact a local TI representative.



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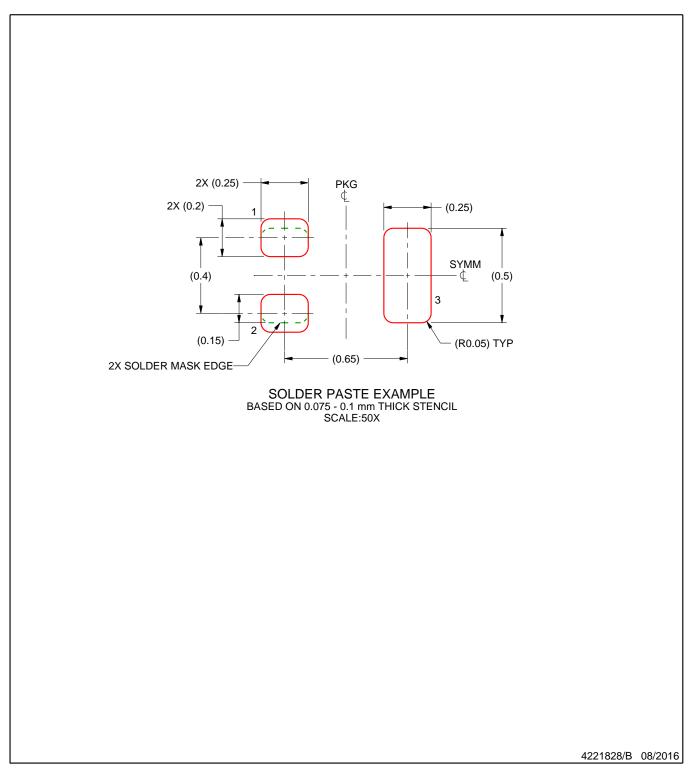


NOTES: (continued)

4. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).



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NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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